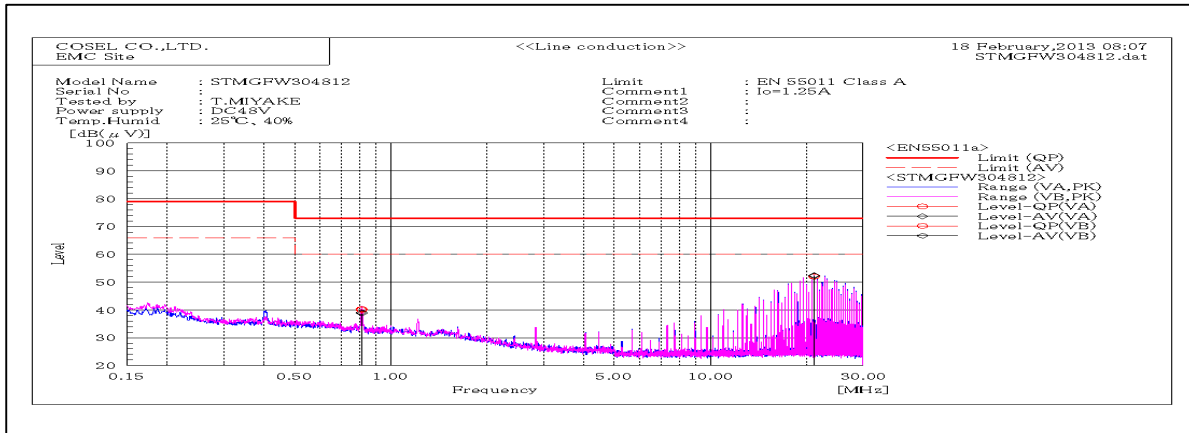
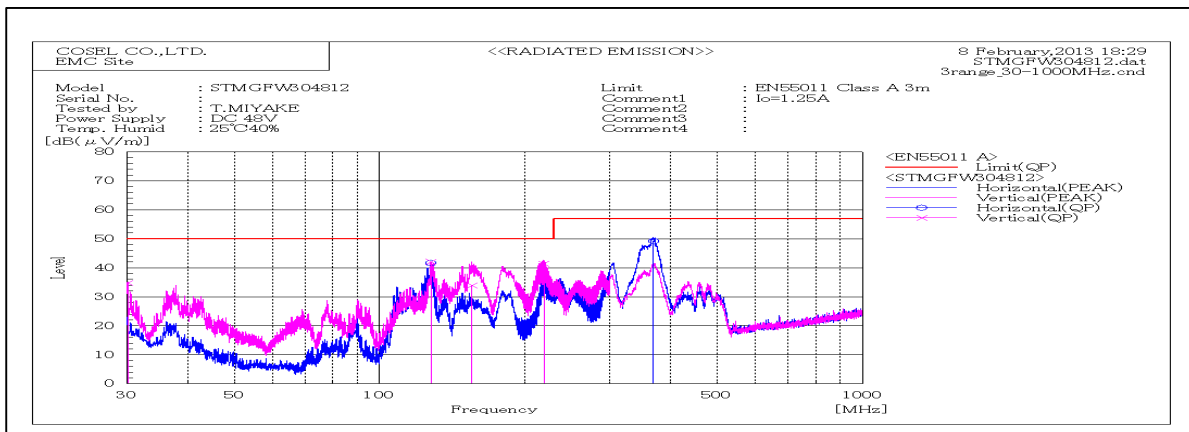


DATA SHEET		Date	18-Feb-13
Model	STMGF304812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake



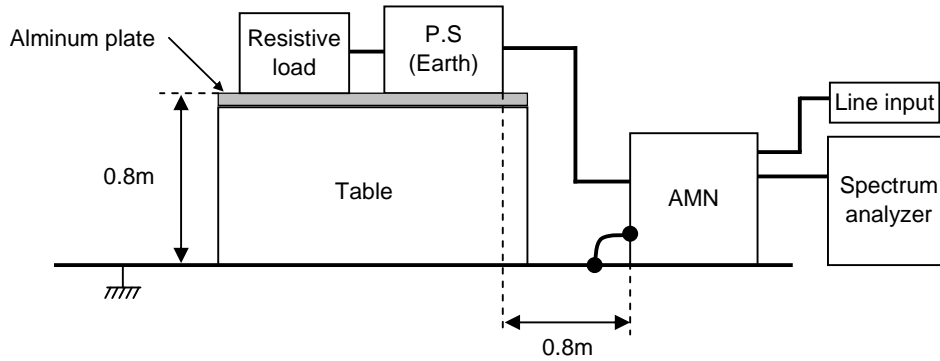
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.81034		VB	19.9	18.7	20.1	40	38.8	73	60	33	21.2	Pass	
0.81127		VA	20.2	19	20.1	40.3	39.1	73	60	32.7	20.9	Pass	
21.1111		VB	30.8	31.1	21.2	52	52.3	73	60	21	7.7	Pass	
21.10925		VA	30.9	31.3	21.2	52.1	52.5	73	60	20.9	7.5	Pass	



Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP					
30.095	V	Stable	48.3		-13.5	34.8	50	15.2	Pass	103	119	
127.713	V	Stable	59.5		-17.4	42.1	50	7.9	Pass	101	14	
127.724	H	Stable	61.3		-19.6	41.7	50	8.3	Pass	141	205	
155.362	V	Stable	52.1		-18.2	33.9	50	16.1	Pass	105	0	
219.225	V	Stable	56.8		-15.4	41.4	50	8.6	Pass	103	168	
369.304	H	Stable	61.5		-12.3	49.2	57	7.8	Pass	108	256	

DATA SHEET		Date	18-Feb-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

1. Line conduction



2. Radiated emission

